





NFORMATION DISCLOSURE STATEMENT BY APPLICANTS

Atty. Docket No. TEX1100

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Applicant:			C
Ryza et al.			ר
Application Number:	Filed:	4.3	~
10/063,049	March 14, 2002	-	_
For:		7	2
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CONTAMINANT FROM A	SUBSTRATE	0	
Group Art Unit	Examiner		
1723	Unknown		

Commissioner for Patents Washington, D.C. 20231

Certification Under 37 C.F.R. §1.8

I hereby certify that the documents listed below are being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231 on

Carpyn Williams

Dear Sir:

Applicants respectfully request, pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, that the art listed on the attached PTO-1449 form be considered and cited in the examination of the above-identified application. A copy of the art is enclosed for the convenience of the Examiner. Furthermore, pursuant to 37 C.F.R. §§ 1.97(g) and (h), no representation is made that a search has been made or that this art is material to patentability of the present application.

While Applicants believe no fees are due, if any fees are due, the Commissioner is hereby authorized to charge Deposit Account No. 50-0456 of Gray Cary Ware & Freidenrich LLP.

Applicants respectfully submit that the claims of Applicants' above-referenced patent application are patentably distinguishable from these references.

Respectfully submitted,

Gray Cary Ware & Freidenrich LLP

Attorneys for Applicant

George R. Meyer

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Date:

12/9

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Sheet

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FORM PTO 1449 US Department of Commerce

Patent and Trademark Office

of 2

Application Number	10/063,049	5
Filing Date	March 14, 2002	
First Named Inventor	Ryza et al.	00
Group Art Unit	1723	
Examiner Name	Unknown	20
Attorney Docket Number	TEX1100	92

		U.S. PATENT	DOCUMENTS			
Examiner Initials Cite		Document Number		Publication	Name of Patentee or Applicant	
	No.	Number	Kind Code (if known)	Date MM-DD-YYYY	of Cited Document	
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	A2	6277753	B1	08/21/01	Mullee et al.	
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Examine Signature			-	Date Considered		



FORM PTO 1449 US Department of Commerce Patent and Trademark Office

Application Number 10/063,049
Filing Date March 14, 2002

First Named Inventor Ryza et al.

Group Art Unit 1723

Examiner Unknown

Sheet 2 of 2 Attorney Docket Number TEX1100

FOREIGN PATENT DOCUMENT

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- 11-11-	B2	PCT	WO 02/15251	Ã1	08/14/00	Tokyo Electron Limited
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		OTHER PRIOR ART NON PATENT LITERATURE D	OCUMENTS	
Examiner Initials	niner Initials Cite No. Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		Date	
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	C2	PERRY, et al., "Chemical Engineers' Handbook", 5th Editi to 21-14 (4 sheets).	on, pp. 21-11	1973
	С3	Phase Diagram for CO ₂ as f http://www.chem.uncc.edu/faculty/murphy/1252/Chapter11B	ound at /sldoo4.htm	February 7, 2002
	C4	Bruan, et al., "Photostrip faces 300 mm, copper and low-k of pages, Semiconductor International.	convergence,"	September 2000
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C7 Gabor, et al., "Block and Random Copolymer Resist Designed for 193 nm Lithography and Environmentally Friendly Supercritical CO ₂ Development," SPIE Vol. 2724, pp. 410-417. C8 Wetmore, et al., "Supercritical Fluid Processing: A New Dry Technique for Photoresist Developing," SPIE Vol. 2438, pp. 694-703.		June 1996		
		June 1995		
Examiner Signature			Date Considered	